

C-MOS Design Tradeoffs

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A faded, light-colored image of a printed circuit board (PCB) layout is visible in the background of the lower half of the slide. The image shows various components, traces, and pads, but is intentionally blurred and dimmed to serve as a background for the text.

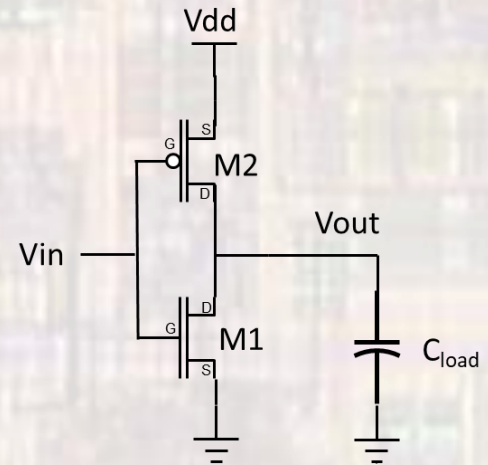
Design Tradeoffs: speed-power

- Total power
 - α – proportion of clock intervals actually switching
 - β – leakage factor

$$P = P_{DC} + P_{SW} + P_{Shoot}$$

$$P = \beta V_{DD} + \alpha C_{load} V_{DD}^2 F + \alpha I_{peak} V_{DD} \left(\frac{t_r + t_f}{2} \right) F$$

All terms a function of V_{DD}



Design Tradeoffs: speed-power

- Power – Speed Tradeoff

Speed:

$$F \propto \frac{1}{t_{pd}}$$

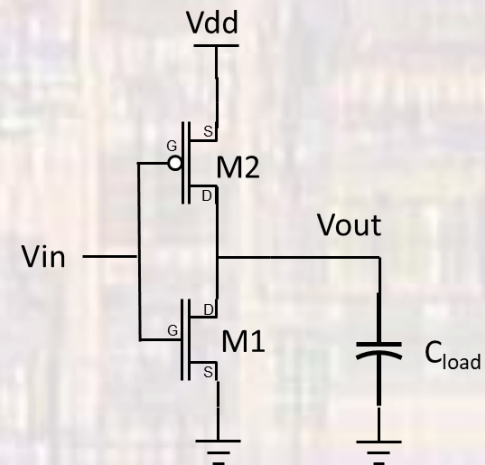
$$t_{pd} = \frac{C_{load} V_{DD}}{\frac{k'_n W}{2L} (V_{DD} - V_t)^2} \propto \frac{1}{V_{DD}}$$

Speed (F) is proportional to V_{DD} / C_{load}

Power:

$$P = \beta V_{DD} + \alpha C_{load} V_{dd}^2 F + \alpha I_{peak} V_{dd} \left(\frac{t_r + t_f}{2} \right) F$$

Power typically dominated by switching power, proportional to $C_{load} * V_{DD}^2 * F$



Design Tradeoffs: speed-power

- Power – Speed Tradeoff
 - Speed(F) $\propto V_{DD} / C_{load}$ but Power $\propto C_{load} * V_{DD}^3$
 - Can't have both low power and fast circuits
- Saved by technology advancements
 - Smaller geometry ICs have:
 - Lower logic gate capacitances \rightarrow smaller loads to drive
 - Shorter channel lengths \rightarrow Higher drive capability
 - Speed(F): $C_{load} \downarrow \rightarrow F \uparrow$
 - Power: $C_{load} \downarrow \rightarrow P \downarrow$

To date, the technology advancements have provided enough speed improvement to allow V_{DD} to be reduced \rightarrow reduced power

Design Tradeoffs: speed-power

- Power – Speed Tradeoff
 - While technology improvements have allowed fast processors at low voltages, this is limited
 - The solution is to use multiple processors in parallel
 - Laptop – 4 cores
 - Only run them when needed
 - Lots of strategies
 - Dynamic Voltage and Frequency Scaling (DVFS)
 - Big/Little
 - High performance cores today
 - $V_{DD} = 0.8V - 1.2V$
 - $F_{clk} = 3-4GHz$

Design Tradeoffs: area - performance

- Matched switching points →
 - large gate sizes → slower operation
 - Higher drive, higher load capacitances
- Matched NAND/NOR gate t_{pD} →
 - large gate sizes → slower operation
 - Higher drive, higher load capacitances
- Minimum gate sizes →
 - large discrepancies in t_{pD}
 - Unmatched switching points
 - Lower drive, lower load capacitance

Design Tradeoffs: area - performance

- Need multiple versions of commonly used gates
 - Minimum gates for low frequency circuits where the variations in t_{pD} and switching points don't matter
 - Speed optimized gates for high frequency circuits
 - Require additional area
 - Scaled gates to drive long wires or external loads
 - High power (very large) gates to manage large current situations
 - Power gating